

Amendments to the Claims

The listing of claims will replace all prior versions, and listings of claims in the application.

1. *(currently amended)* An ESD protection circuit, comprising:

one or more first diodes on a first area of P-substrate coupled in series between a supply voltage and a terminal pad;

a second diode on said first area of P-substrate coupled to a ground, said second diode having an n+ region; and

one or more third diodes on a second area of P-substrate coupled in series between said terminal pad and said second diode, each of said one or more third diodes having a deep N-well that separates said second area of P-substrate from said first area of P-substrate ~~wherein said one or more third diodes are configured to enable a voltage on an interconnection node between said one or more third diodes and said second diode that is different from ground;~~

~~wherein said ESD protection circuit increases the allowable signal swing at said terminal pad.~~

2. *(currently amended)* The ESD protection circuit of claim 1, wherein said one or more third diodes each includes an n+ region on a said second area of P-substrate surrounded by a said deep N-well.

3. *(currently amended)* The ESD protection circuit of claim [[2]]1, wherein said deep N-well ~~separates said area of P-substrate from a common area of P-substrate~~

isolates a voltage on an interconnection node between said one or more third diodes and said second diode from said ground.

4. *(currently amended)* The ESD protection circuit of claim ~~[[3]]~~1, wherein said ~~common~~ first area of P-substrate is coupled to said ground.

5. *(currently amended)* The ESD protection circuit of claim 1, wherein ~~said~~ an allowable signal swing at said terminal pad is greater than said supply voltage plus 1.4 V.

6. *(currently amended)* The ESD protection circuit of claim 1, wherein a forward turn-on voltage of each of said one or more first diodes, said second diode, and said one or more third diodes is approximately 0.7 V.

7. *(currently amended)* An ESD protection circuit, comprising:

one or more ~~of a~~ first diodes on a first area of P-substrate coupled in series between a supply voltage and a terminal pad, each of said one or more first diodes having a p+ region in an N-well;

a second diode on said first area of P-substrate coupled to a ground, said second diode having an n+ region; and

one or more ~~of a~~ third diodes on a second area of P-substrate coupled in series between said terminal pad and said second diode, ~~wherein~~ each of said one or more third diodes ~~includes~~ having an n+ region on an said second area of P-substrate separated by a deep N-well from ~~a common~~ said first area of P-substrate;

~~wherein said ESD protection circuit increases the allowable signal swing at said terminal pad.~~

8. *(canceled)*

9. *(canceled)*

10. *(currently amended)* The ESD protection circuit of claim 7, wherein said ~~common~~ first area of P-substrate is coupled to said ground.

11. *(currently amended)* The ESD protection circuit of claim 7, wherein said ~~an~~ an allowable signal swing at said terminal pad is greater than said supply voltage plus 1.4 V.

12. *(currently amended)* The ESD protection circuit of claim 7, wherein a forward turn-on voltage of each of said one or more first diodes, said second diode, and said one or more third diodes is approximately 0.7 V.

13. *(currently amended)* An ESD protection circuit, comprising:

a first diode on a first area of P-substrate having a cathode coupled to a supply voltage and an anode coupled to a cathode of a second diode, said second diode on said first area of P-substrate having an anode coupled to a terminal pad; and

a third diode on a second area of P-substrate having a cathode coupled to said terminal pad and an anode coupled to a cathode of a fourth diode, said fourth diode on

said first area of P-substrate having an anode coupled to a ground, wherein said third diode includes an n+ region on ~~an~~ said second area of P-substrate separated by a deep N-well from ~~a common~~ said first area of P-substrate, and wherein said fourth diode includes an n+ region on said first area of P-substrate;

~~wherein said ESD protection circuit increases the allowable signal swing at said terminal pad.~~

14. *(currently amended)* The ESD protection circuit of claim 13, wherein said first diode and said second diode each includes an n+ region in an N-well on said ~~common~~ first area of P-substrate.

15. *(currently amended)* The ESD protection circuit of claim 13, wherein ~~said fourth diode includes an n+ on said common area of P-substrate~~ an interconnection node between said third diode and said fourth diode is isolated from said ground.

16. *(currently amended)* The ESD protection circuit of claim 13, wherein said ~~common~~ first area of P-substrate is coupled to said ground.

17. *(currently amended)* The ESD protection circuit of claim 13, wherein ~~said~~ an allowable signal swing at said terminal pad is greater than said supply voltage plus 1.4 V.

18. *(currently amended)* The ESD protection circuit of claim 13, wherein a forward turn-on voltage of each of said first diode, said second diode, said third diode, and said fourth diode is approximately 0.7 V.